Course	Course Name	L-T-P-	Year of	
code		Credits	Introduction	
ME312	METROLOGY AND INSTRUMENTATION	3-0-0-3	2016	

Prerequisite: Nil

Course Objectives:

- To understand the working of linear and angular measuring instruments.
- To familiarize with the working of optical measuring instruments and fundamentals of limits and limit gauges.
- To give basic idea about various methods for measurement of screw thread and surface finish parameters.
- To give an exposure to advanced measuring devices and machine tool metrology.
- To provide students an overview of mechanical measurement systems and principle of instruments for motion and dimension measurement.
- To provide basic idea about working principle and applications of devices for measurement of force and torque; strain and stress and temperature.

Syllabus

Introduction to Metrology - Errors in Measurement- Basic standards of length - Linear Measurement, Comparators - Angular Measurement - Limits and Limit gauges - Optical Measuring Instruments - Screw thread measurement - Measurement of surface texture - Machine tool metrology - Coordinate Measuring Machine (CMM) and Machine Vision.

Introduction to Mechanical Measurement - Motion and Dimension measurement, Strain and Stress Measurement - Measurement of Force, Torque and Temperature Measurement.

Expected outcome:

The students will be able to

- i. Understand the working of linear and angular measuring instruments.
- ii. Know the fundamentals of limits and limit gauges, various methods for measurement of screw thread and surface roughness parameters and the working of optical measuring instruments.
- iii. Get an exposure to advanced measuring devices and machine tool metrology.
- iv. Acquire an overview of mechanical measurement systems and principle of instruments for motion and dimension measurement.
- v. Get basic idea about working principle and applications of devices for measurement of force and torque; strain and stress and temperature.

Text books

- 1. Anand K Bewoor, Vinay A Kulkarni, Metrology & Measurement, McGraw-Hill, 2009
- 2. Ernest O. Doebelin, Dhanesh N. Manik, Measurement Systems Application and Design, McGraw-Hill, 2004
- 3. Galyer J.F.W., Schotbolt C.R., Metrology for Engineers, ELBS, 1990
- 4. Thomas G. Beckwith, John H. L., Roy D. M., Mechanical Measurements, 6/E, Pearson Prentice Hall, 2007

Reference books

- 1. ASME, Hand book of Industrial Metrology, 1998
- Hume K. J., Engineering Metrology, Macdonald &Co. Ltd.,1990
 J.P.Holman, Experimental Methods for Engineers, Mcgraw-Hill, 2007
- 4. Sharp K.W.B., Practical Engineering Metrology, Sir Isaac Pitman & Sons Ltd., 1958

Module Concept of measurement:-Introduction to Metrology; Need for high precision measurements; Terminologies in Measurement- Precision, accuracy, sensitivity, calibration. Image: Image		Course Plan		
high precision measurements; Terminologies in Measurement-Precision, accuracy, sensitivity, calibration. 1 Errors in Measurement, types of errors, Abbe's Principle. 1 Basic standards of length- Line standard, End standards, 1 Wavelength standard; Various Shop floor standards. 1 Linear Measurement – Slip gauges, wringing, grades; Surface plate; Dial indicators; Height gauges and Vernier calipers. 1 Comparators- mechanical, electrical, optical and pneumatic. 1 Angular Measurement – Bevel protractor; Sine Bar, principle and use of sine bar, sine centre; Angle gauges. 1 Sprit level; Angle Dekkor; Clinometers. 1 Limits and Limit gauges – Making to suit, selective assembly, 1 1 systems of limits and fits; Types of fits; Hole basis system and Shaft basis system. 1 Standard systems of limits and fits; Shaft and Hole system; Tolerance, allowance and deviation (as per BIS). 1 Simple problems on tolerance and allowance, shaft and hole system. 1 Limit Gauges – GO and NO GO gauges; types of limit gauges. 1 Gauge design - Taylor's principle of gauging; Gauge tolerance, disposition of gauge tolerance, wear allowance. 1 Optical Measuring Instruments: - Benefits of using light waves as standards; Monochromatic light; Principle of Interference. 1 Interferometers – NPL flatness	Module	TECHNContents LOGICA	Hours	Sem. Exam.
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		Measurement of pitch; Measurement of effective diameter with	1	
		Measurement of flank angle and form by profile projector and	1	

	microscope.			
III	Measurement of surface texture – Meaning of surface texture, roughness and waviness; Analysis of surface traces, peak to valley height, R.M.S. value, Centre Line Average and R _a value, Rt, Rz etc.	1		
	Methods of measuring surface roughness – Stylus probe, Tomlinson surface meter, Talysurf; Terms used in surface roughness measurement – assessment length, roughness width cut- off, sampling length and evaluation length.	1 15%		
	Interference method for measuring surface roughness – using optical flat and interferometers.	1		
	Autocollimator, principle and use of autocollimator.	1		
	Machine tool metrology – Alignment testing of machine tools like lathe, milling machine, drilling machine.	1		
	Advanced measuring devices – Laser interferometers.	1		
	Coordinate Measuring Machine (CMM) – Introduction to CMM; Components and construction of CMM.	1	4 = 0 /	
IV	Types of CMM; Advantages and application of CMM	1	15%	
	CMM probes, types of probes – contact probes and non contact probes	1		
	Machine Vision – Introduction to machine vision, functions, applications and advantages of machine vision.			
	Steps in machine vision	1	1	
	SECOND INTERNAL EXAMINATION			
	Introduction to Mechanical Measurement – significance of mechanical measurement; Fundamental methods of measurement; Classification of measuring instrument.	1		
	Stages in generalized measuring system – Sensor-Transducer stage, Signal-Conditioning stage, Readout-Recording stage; Types of input quantities; Active and Passive transducers.	1	20%	
V	Performance characteristic of measuring devices – Static characteristics – Accuracy, Precision, Repeatability, Sensitivity, Reproducibility, Drift, Resolution, Threshold, Hysteresis, Static calibration.	1		
	Dynamic characteristics- different order systems and their response-, Measuring lag, Fidelity, Dynamic error; Types of errors in measurement.	1		
	Transducers – Working, Classification of transducers.	1		
	Motion and Dimension measurement – LVDT – Principle, applications, advantages and limitations.	1		
V1	Strain and Stress Measurement - Electrical resistance strain gauge - Principle, operation.	1		
	Measurement of Force and Torque – Strain-Gauge Load Cells, Hydraulic and Pneumatic load cells – basic principle and three component force measurement using piezoelectric quartz crystal.	1		
	Torque Measurement – Dynamometers – Mechanical, Hydraulic and Electrical.	1		
	Vibration measurement – Vibrometers and Accelerometers – Basic principles and operation.	1		

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Question Paper Pattern

Maximum marks: 100

Time: 3 hrs

The question paper should consist of three parts

Part A

There should be 2 questions each from module I and II Each question carries 10 marks Students will have to answer any three questions out of 4 (3X10 marks = 30 marks)

Part B

There should be 2 questions each from module III and IV Each question carries 10 marks Students will have to answer any three questions out of 4 (3X10 marks = 30 marks)

Part C

There should be 3 questions each from module V and VI Each question carries 10 marks Students will have to answer any four questions out of 6 (4X10 marks =40 marks)

Note: Each question can have a maximum of four sub questions, if needed.